

Description

The AP640P is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

General Features

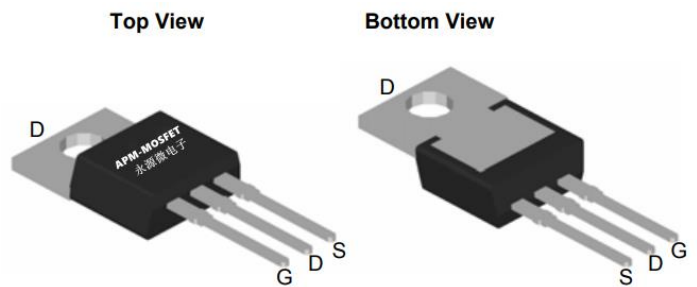
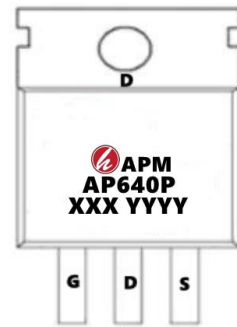
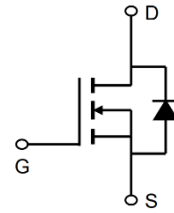
$V_{DS} = 200V$ $I_D = 18A$

$R_{DS(ON)} < 150m\Omega$ @ $V_{GS}=10V$ (Type: 120m Ω)

Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP640P	TO-220-3L	AP640P XXX YYYY	1000

Absolute Maximum Ratings ($T_C=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
		TO-220-3L	
V_{DS}	Drain-Source Voltage ($V_{GS} = 0V$)	200	V
I_D	Continuous Drain Current	18	A
I_{DM}	Pulsed Drain Current (note1)	72	A
V_{GS}	Gate-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy (note2)	340	mJ
I_{AR}	Avalanche Current (note1)	15	A
E_{AR}	Repetitive Avalanche Energy (note1)	8.3	mJ
P_D	Power Dissipation ($T_C = 25^{\circ}C$)	104	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	$-55 \sim +150$	$^{\circ}C$
R_{thJC}	Thermal Resistance, Junction-to-Case	1.2	$^{\circ}C/W$
R_{thJA}	Thermal Resistance, Junction-to-Ambient	62.5	$^{\circ}C/W$

Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	200	220	--	V
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 200V, V_{GS} = 0V, T_J = 25^{\circ}\text{C}$	--	--	5	μA
		$V_{DS} = 160V, V_{GS} = 0V, T_J = 125^{\circ}\text{C}$	--	--	100	
IGSS	Gate-Source Leakage	$V_{GS} = \pm 20V$	--	--	± 100	nA
VGS(th)	Gate-Source Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	3.0	4.0	V
RDS(on)	Drain-Source On-Resistance (Note3)	$V_{GS} = 10V, I_D = 9A$	--	120	150	m Ω
Ciss	Input Capacitance	$V_{GS} = 0V,$ $V_{DS} = 25V, f = 1.0\text{MHz}$	--	1318	--	pF
Coss	Output Capacitance		--	180	--	
Crss	Reverse Transfer Capacitance		--	75	--	
Qg	Total Gate Charge	$V_{DD} = 160V, I_D = 18A, V_{GS} = 10V$	--	41	--	nC
Qgs	Gate-Source Charge		--	5.5	--	
Qgd	Gate-Drain Charge		--	19.5	--	
td(on)	Turn-on Delay Time	$V_{DD} = 100V, I_D = 18A, R_G = 25\Omega$	--	24	--	ns
tr	Turn-on Rise Time		--	45	--	
td(off)	Turn-off Delay Time		--	101	--	
tf	Turn-off Fall Time		--	95	--	
Is	Continuous Body Diode Current	$T_C = 25^{\circ}\text{C}$	--	--	18	A
ISM	Pulsed Diode Forward Current		--	--	72	
VSD	Body Diode Voltage	$T_J = 25^{\circ}\text{C}, I_{SD} = 18A, V_{GS} = 0V$	--	--	1.4	V
trr	Reverse Recovery Time	$V_{GS} = 0V, I_S = 18A, di_F/dt = 100A/\mu s$	--	230	--	ns
Qrr	Reverse Recovery Charge		--	1.8	--	μC

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The EAS data shows Max. rating . IAS = 15A, VDD = 50V, RG = 25 Ω , Starting TJ = 25 $^{\circ}\text{C}$
- 3、The test condition is Pulse Test: Pulse width $\leq 300\mu s$, Duty Cycle $\leq 1\%$
- 4、The power dissipation is limited by 150 $^{\circ}\text{C}$ junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

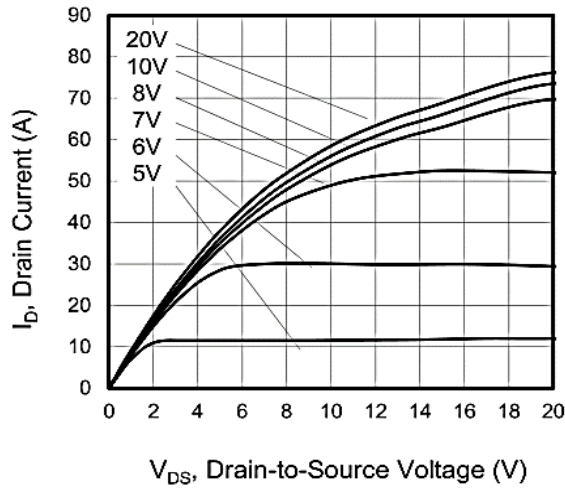
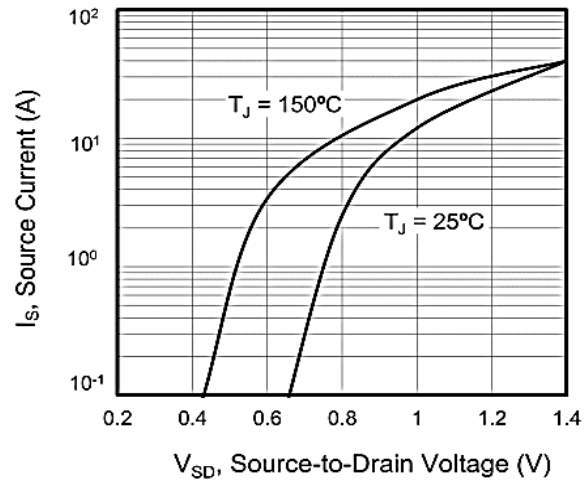
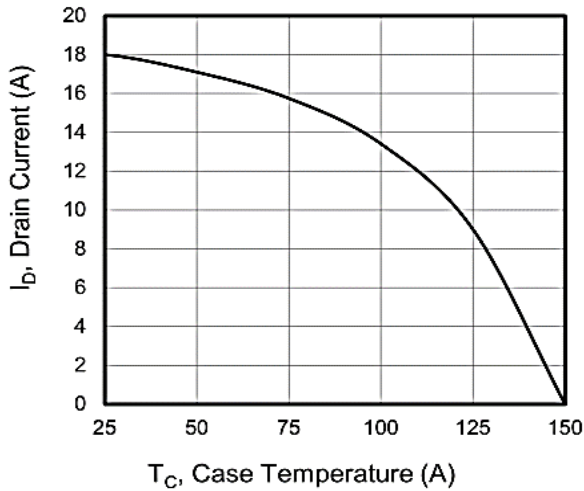
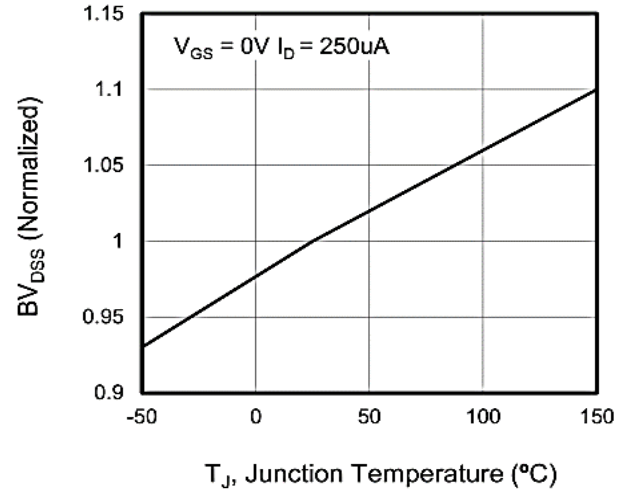
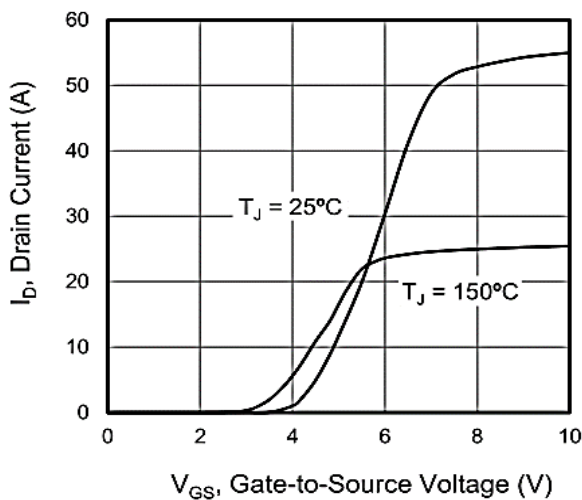
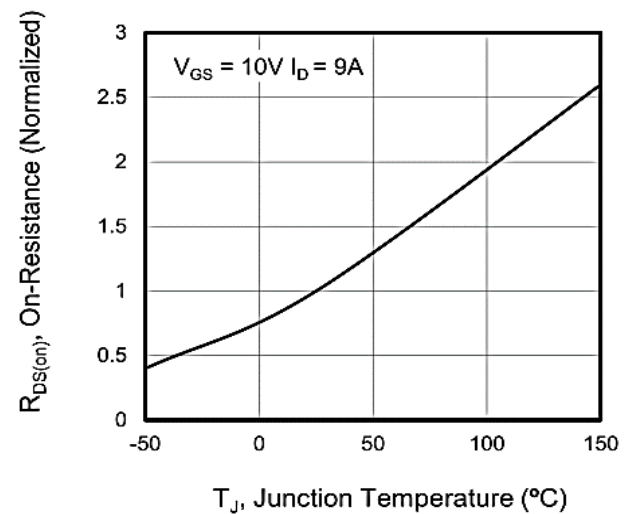
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AP640P (AP18N20P)

200V N-Channel Enhancement Mode MOSFET

Typical Characteristics

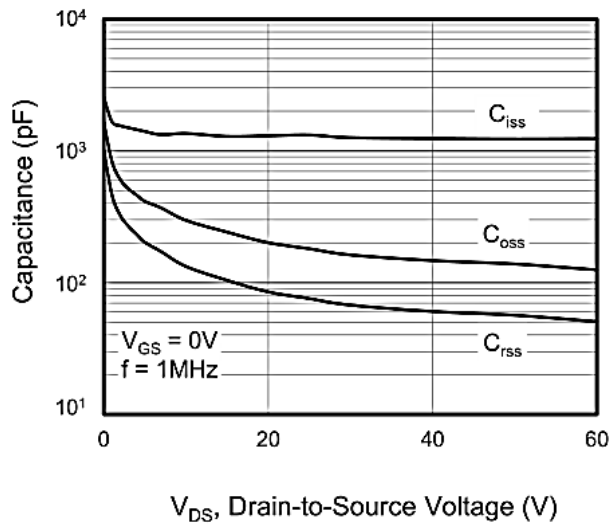
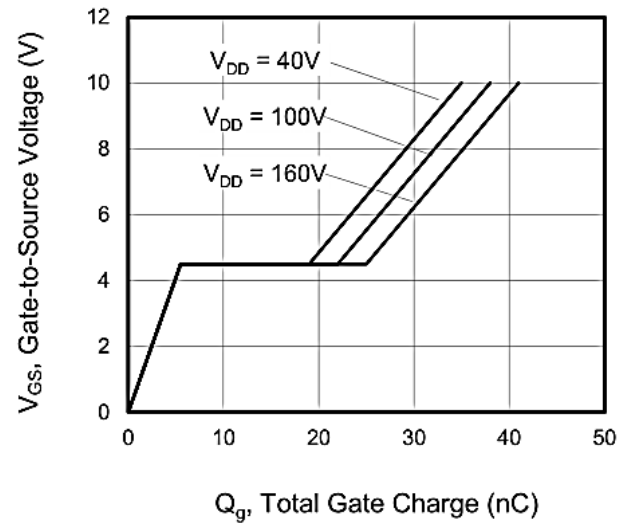
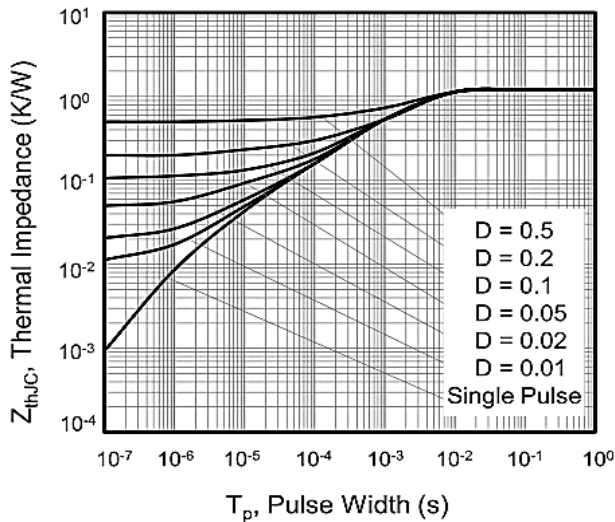
**Figure 1. Output Characteristics ($T_J = 25^\circ\text{C}$)****Figure 2. Body Diode Forward Voltage****Figure 3. Drain Current vs. Temperature****Figure 4. BV_{DSS} Variation vs. Temperature****Figure 5. Transfer Characteristics****Figure 6. On-Resistance vs. Temperature**

**APM**

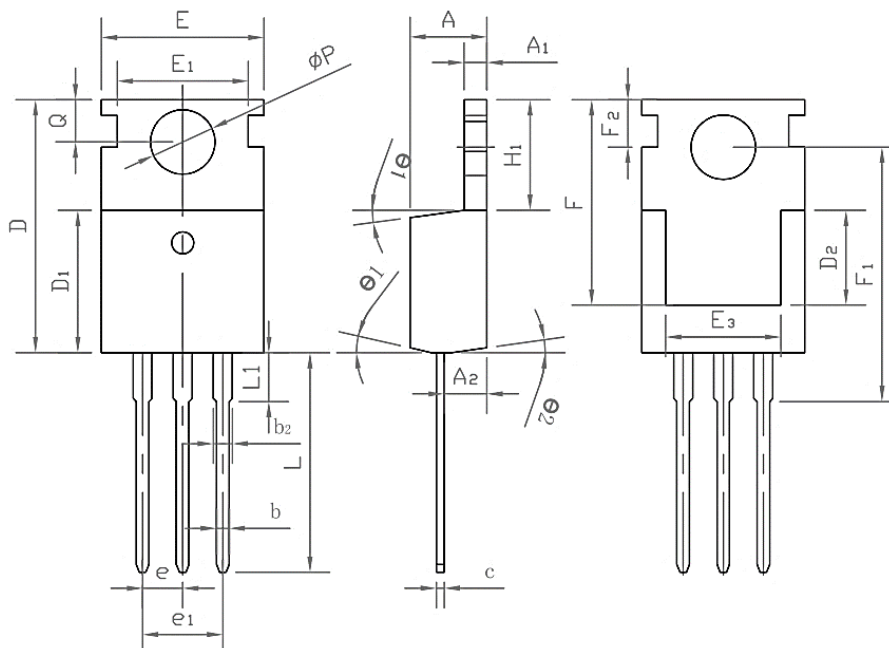
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AP640P (AP18N20P)

200V N-Channel Enhancement Mode MOSFET

**Figure 7. Capacitance****Figure 8. Gate Charge****Figure 10. Transient Thermal Impedance**

Package Mechanical Data-TO-220-3L-SLK



Symbol	Common		
	mm		
	Mim	Nom	Max
A	4.27	4.57	4.87
A1	1.15	1.30	1.45
A2	2.10	2.40	2.70
b	0.70	0.80	1.00
b2	1.17	1.27	1.50
D	0.40	0.50	0.65
D1	8.80	9.10	9.40
D2	5.70	6.70	7.00
E	9.70	10.00	10.30
E1	-	8.70	-
E2	9.63	10.00	10.35
E3	7.00	8.00	8.40
e		0.37	
e1		0.10	
H1	6.00	6.50	6.85
L	12.75	13.50	13.90
L1	-	3.10	3.40
Φp	3.45	3.60	3.75
Q	2.60	2.80	3.00
θ1	4°	7°	10°
θ2	0°	3°	6°
F	13.30	13.50	13.70
F1	15.50	15.90	16.30
F2	2.80	3.00	3.20

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Edition	Date	Change
Rve1.0	2019/1/31	Initial release
Rve1.1	2021/9/26	Change of specification forma

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